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Fairchild Semiconductor FDS2070N3

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February 2004

FDS2070N3

150V N-Channel PowerTrench^o MOSFET

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low $R_{\text{DS}(\text{ON})}$ in a small package.

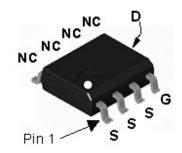
Applications

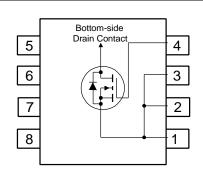
- · Synchronous rectifier
- DC/DC converter

FLMP SO-8

Features

- 4.1 A, 150 V. $R_{DS(ON)} = 78 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 88 \text{ m}\Omega$ @ $V_{GS} = 6.0 \text{ V}$
- High performance trench technology for extremely low R_{DS(ON)}
- · High power and current handling capability
- Fast switching, low gate charge (38nC typical)
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		150	V
V _{GSS}	Gate-Source Voltage		± 20	V
I _D	Drain Current - Continuous	(Note 1a)	4.1	A
	- Pulsed		30	
P _D	Power Dissipation for Single Operation	(Note 1a)	3.0	W
		(Note 1b)	1.8	
T _J , T _{STG}	Operating and Storage Junction Temperat	ture Range	-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	0.5	

Package Marking and Ordering Information

		<u> </u>			
Device Marking	Device	Reel Size	Tape width	Quantity	
FDS2070N3	FDS2070N3	13"	12mm	2500 units	

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Electrical Characteristics $T_A = 25$ °C unless otherwise noted Symbol **Parameter Test Conditions** Min Typ Max Units **Drain-Source Avalanche Ratings** Single Pulse, $V_{DD} = 150 \text{ V}$, $I_D = 10 \text{ A}$ W_{DSS} Drain-Source Avalanche Energy 440 mJ L = 8.8 mHDrain-Source Avalanche Current 10 Α I_{AR} **Off Characteristics** Drain-Source Breakdown $I_D = 250 \, \mu A$ 150 ٧ $V_{GS} = 0 V$ BV_{DSS} Voltage Breakdown Voltage Temperature ΔBV_{DSS} $I_D = 250 \mu A$, Referenced to $25^{\circ}C$ 154 mV/°C ΔT_J Zero Gate Voltage Drain Current $V_{DS} = 120 \text{ V}, \quad V_{GS} = 0 \text{ V}$ I_{DSS} μΑ Gate-Body Leakage $V_{GS} = \pm 20 \text{ V}, \ V_{DS} = 0 \text{ V}$ nΑ I_{GSS} ±100 On Characteristics (Note 2) ٧ Gate Threshold Voltage $V_{DS} = V_{GS}$ $I_D = 250 \, \mu A$ 2 2.6 4 $V_{GS(th)}$ $\Delta V_{GS(th)}$ Gate Threshold Voltage $I_D = 250 \mu A$, Referenced to $25^{\circ}C$ -7 mV/°C Temperature Coefficient $\Delta T_{.i}$ $I_D = 4.1 \text{ A}$ R_{DS(on)} Static Drain-Source $V_{GS} = 10 \text{ V},$ 58 78 $\mathsf{m}\Omega$ On-Resistance $V_{GS} = 6.0V$, $I_D = 3.8 A$ 61 88 $I_D = 4.1 \text{ A}, T_J = 125^{\circ}\text{C}$ 112 160 $V_{GS} = 10 \text{ V},$ Forward Transconductance $V_{DS} = 10 \text{ V}, \quad I_{D} = 4.1 \text{ A}$ 24 S **g**FS **Dynamic Characteristics** $V_{DS} = 75 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ $C_{\mathsf{is}\underline{\mathsf{s}}}$ 1884 Input Capacitance pF f = 1.0 MHz Output Capacitance 102 рF C_{oss} C_{rss} Reverse Transfer Capacitance 35 pF Gate Resistance $R_{\text{\scriptsize G}}$ $V_{GS} = 15 \text{ mV}, f = 1.0 \text{ MHz}$ 1.6 Ω Switching Characteristics (Note 2) $V_{DD} = 75 \text{ V},$ $I_D = 1 A$ Turn-On Delay Time 20 10 ns $V_{GS} = 10 \text{ V}, \quad R_{GEN} = 6 \Omega$ Turn-On Rise Time 6 12 t_{r} ns Turn-Off Delay Time $t_{\text{d(off)}} \\$ 40 64 ns Turn-Off Fall Time 20 36 tf ns Q_g $V_{DS} = 75 V$, $I_D = 4.1 A$ **Total Gate Charge** 38 53 nC $V_{GS} = 10 \text{ V}$ Q_{gs} Gate-Source Charge 8 nC

 $Q_{g\underline{d}}$ **Drain-Source Diode Characteristics and Maximum Ratings**

Is	Maximum Continuous Drain-Source Diode Forward Current					2.5	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.5 \text{ A}$	(Note 2)		0.75	1.2	V
t _{rr}	Diode Reverse Recovery Time	I _F = 4.1A			75		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$	(Note 2)		404		nC

Notes:

1. R BLA is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



40°C/W when mounted on a 1in² pad of 2 oz copper



85°C/W when mounted on a minimum pad of 2 oz

11

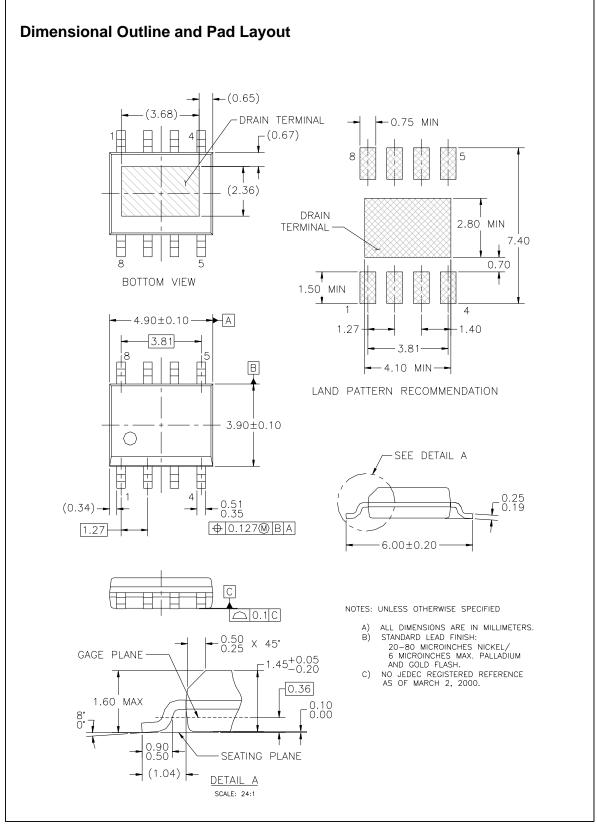
Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width < $300\mu s$, Duty Cycle < 2.0%

Gate-Drain Charge

nC

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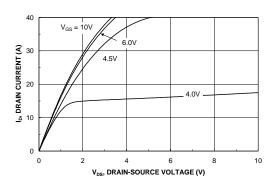






2.6

0.2 L -50 I_D = 4.1 A V_{GS} = 10V



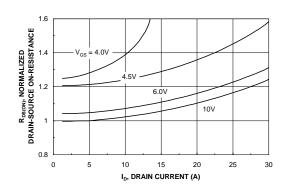


Figure 1. On-Region Characteristics.

0.1 (CE (OHM))

125 150

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

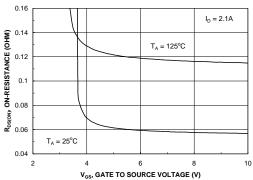


Figure 3. On-Resistance Variation with Temperature.

50

T_J, JUNCTION TEMPERATURE (°C)

75

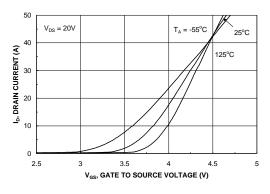


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

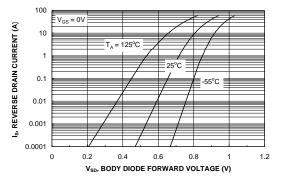
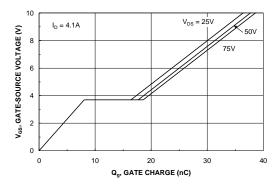


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.







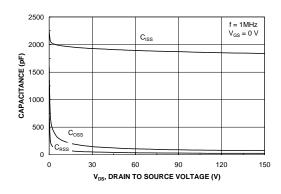
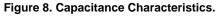
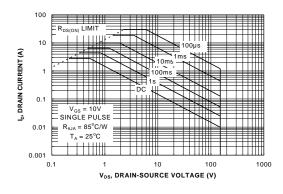


Figure 7. Gate Charge Characteristics.





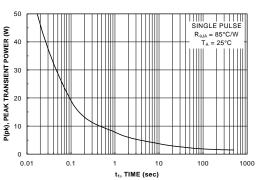


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

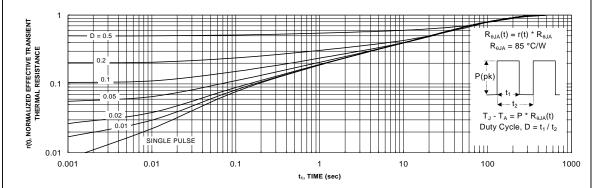


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.



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EcoSPARK™	GTO™ .	MSX TM	QT Optoelectronics™	TinyLogic [®]
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